

<b>Notice of References Cited</b>	Application/Control No. 10/736,533	Applicant(s)/Patent Under Reexamination OGAWA, KENICHI	
	Examiner Lynn D. Reed	Art Unit 2112	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0090058	07-2002	Yasuda et al.	378/205
*	B	US-6,055,295	04-2000	Murthy et al.	378/151
*	C	US-4,766,603	08-1988	Okabe et al.	378/152
*	D	US-6,990,368	01-2006	Simon et al.	600/425
*	E	US-5,870,450	02-1999	Khutoryansky et al.	378/197
*	F	US-2002/0045817	04-2002	Ichihashi, Masahide	600/425
*	G	US-5,450,464	09-1995	Sakakibara, Jun	378/98.2
*	H	US-6,990,368	01-2006	Simon et al.	600/425
*	I	US-2002/0041654	04-2002	Hayashi, Takashi	378/196
*	J	US-2004/0005031	01-2004	Akutsu et al.	378/156
*	K	US-5,917,882	06-1999	Khutoryansky et al.	378/116
*	L	US-6,577,889	06-2003	Ichihashi, Masahide	600/425
*	M	US-6,052,476	04-2000	Qian et al.	382/130

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.